

R&D activity at LMA

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outline

substrates

- thermo-elastic damping of disks

amorphous coatings

- direct measurement of thermal noise
- structure and mechanical loss

for more details
Granata & al., GWADW14, Takayama

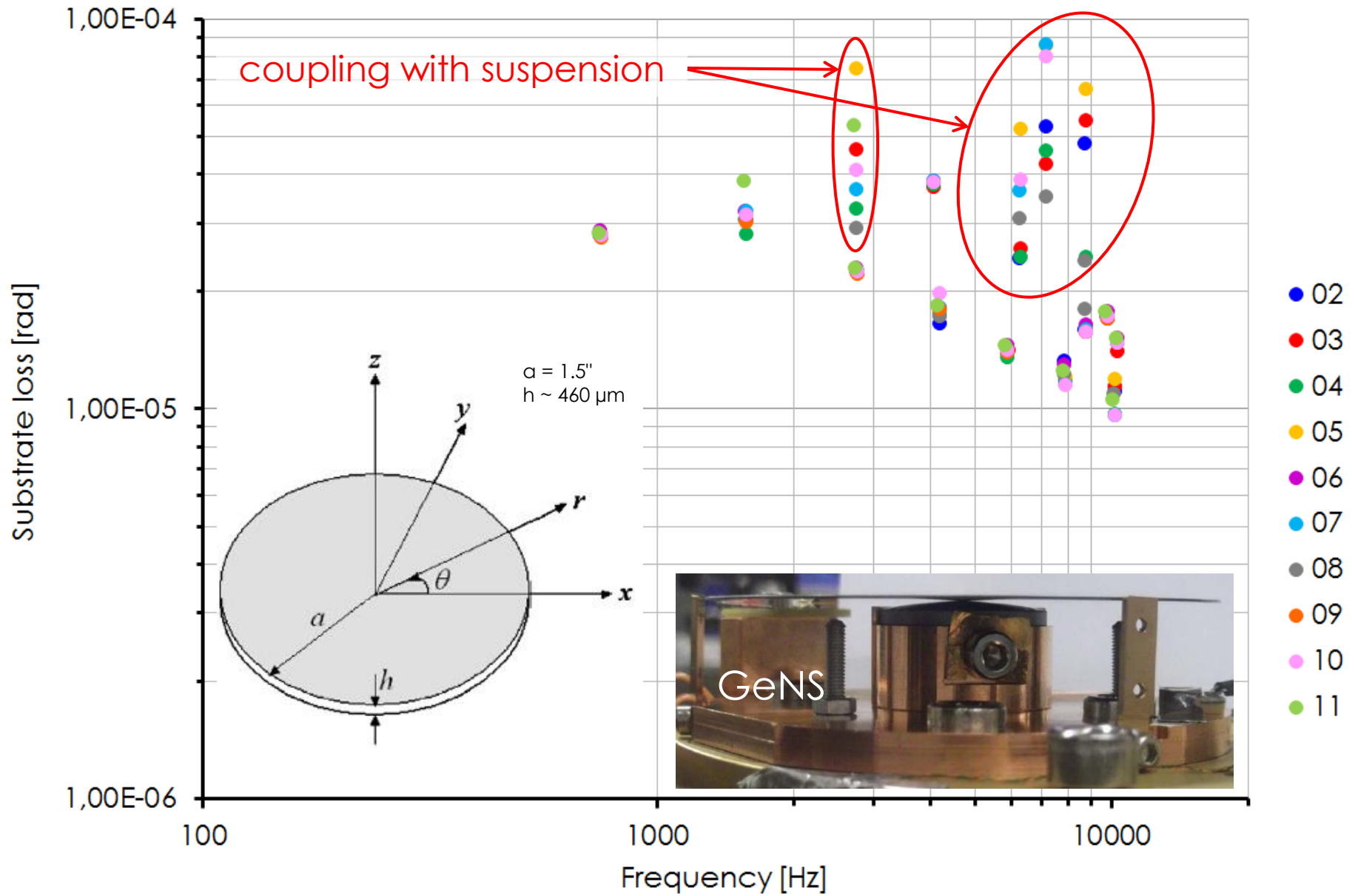
warning

coatings used in these studies
are not the same
as those of detector test masses

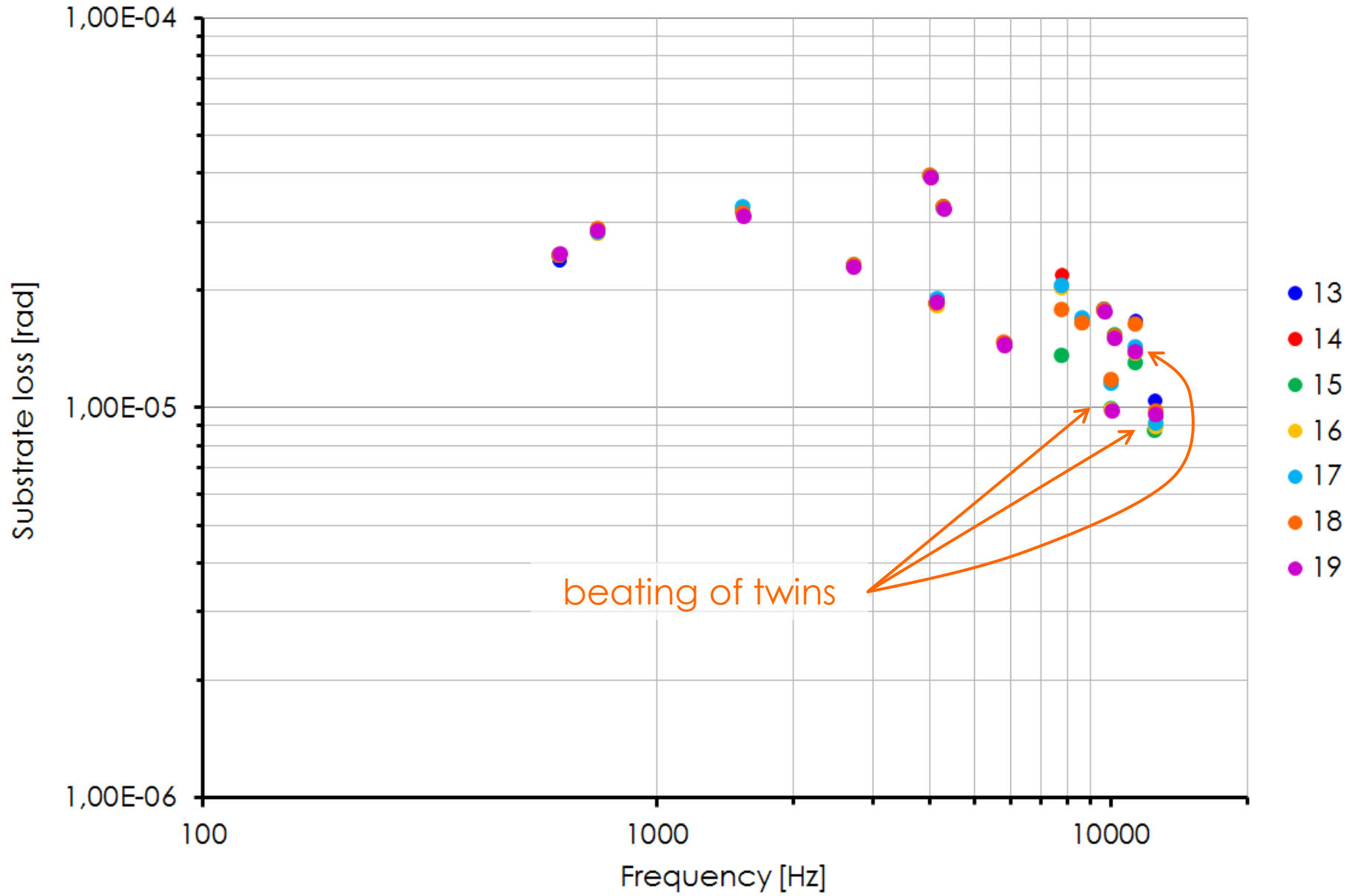
- different ion-beam-sputtering machines
- different deposition parameters

thermo-elastic damping of disks

patterns



patterns



evidences

GeNS

- high repeatability

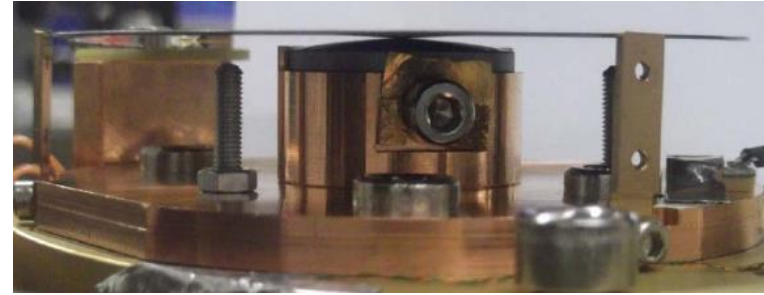
$$\Delta f/f \sim 10^{-4}$$

$$\Delta Q/Q < 5\%$$

- very low excess loss \leftrightarrow at low temperature: $Q_{0,2} = 2.2 \times 10^8$

$$Q_{1,4} = 8.3 \times 10^7$$

$$Q_{2,2} = 1.1 \times 10^8$$



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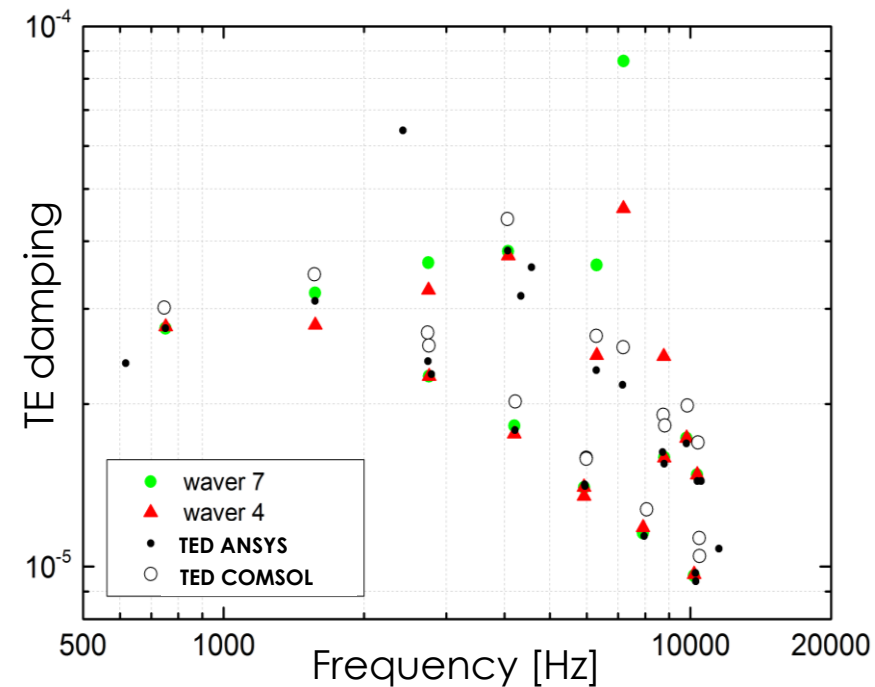
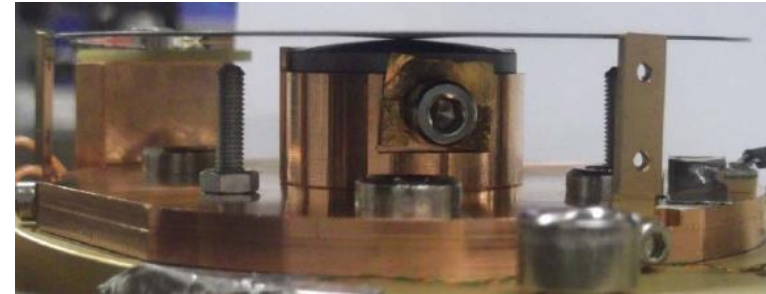
- independent simulations

ANSYS + analytical

COMSOL

modes and loss confirmed

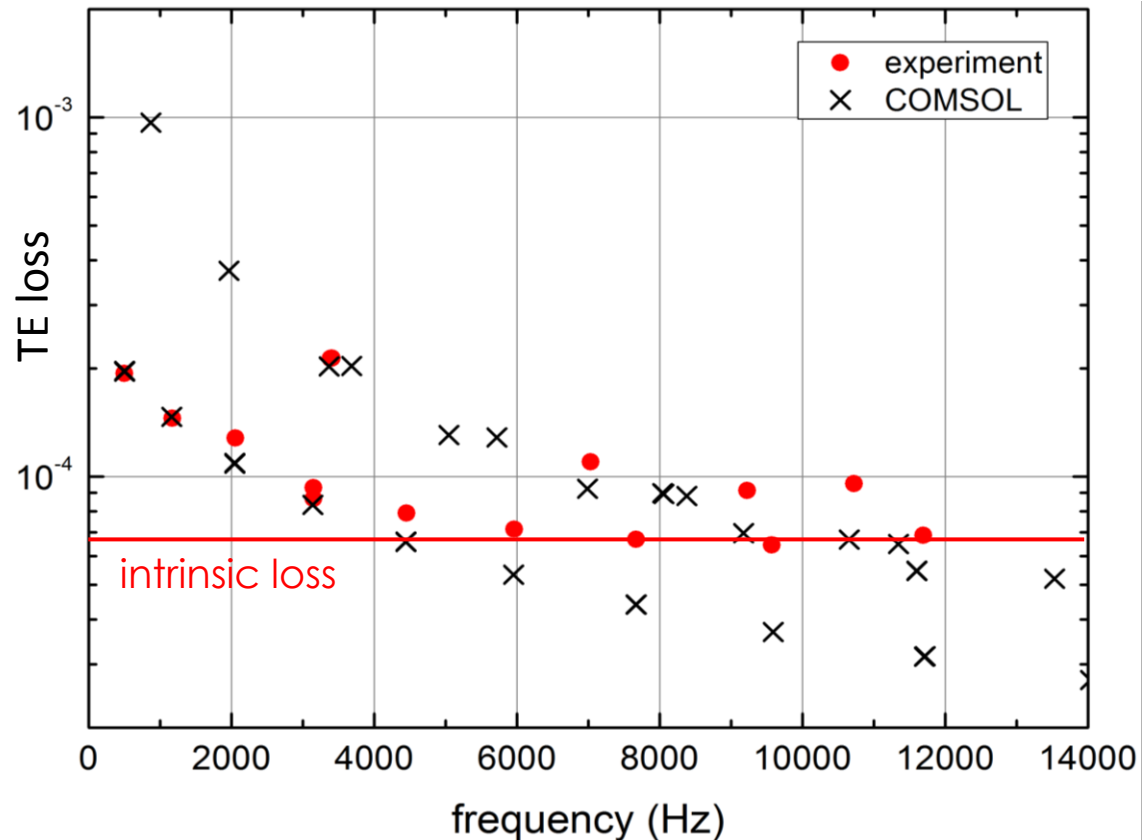
\rightarrow mode families are for real



isotropic sample

- $d = 3"$, $t = 0.8$ mm, alpha-brass (Cu 64%, Zn 36%)
- simulations predict mode families
- preliminary measurements confirm expectations

→ all disks feature
mode-dependent
thermo-elastic damping



theory

correction of Zener's equation

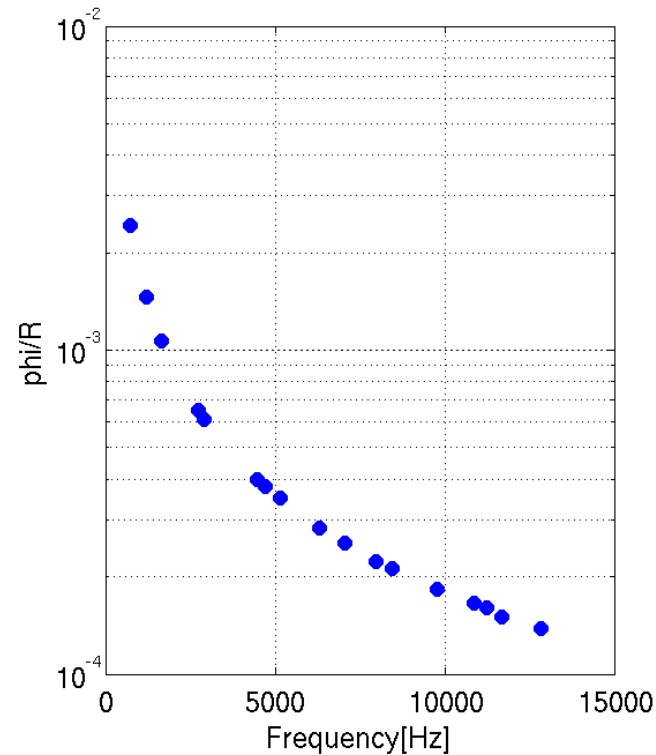
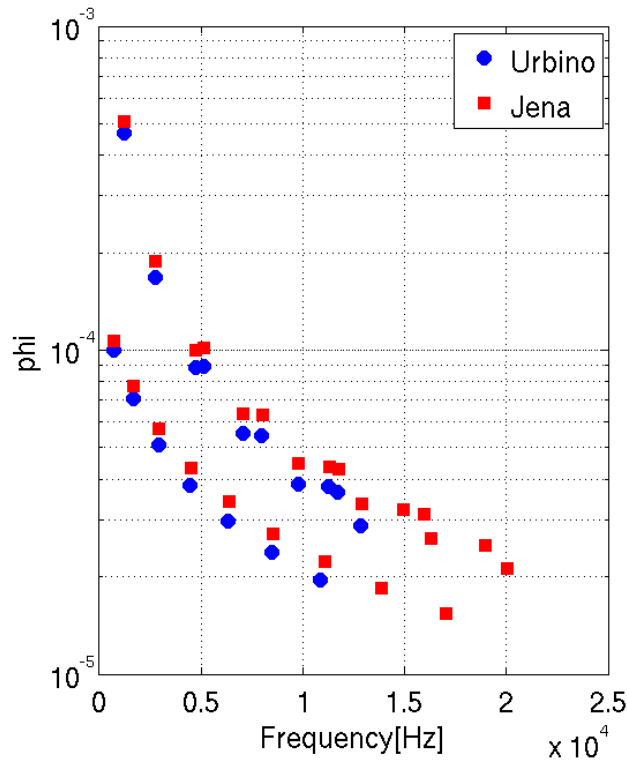
- energy-based approach

→ introducing R = dilation energy/total energy

$$\phi_{TE}^{(Z)} = \frac{Y \alpha^2 T_0}{\rho C} \frac{\omega \tau}{1 + (\omega \tau)^2}$$

$$R = R_0 (1 + \sigma_{xx} \sigma_{yy}) / Y$$

$R_0 = Y/9K$
same as for rods



paper in preparation

direct measurement of coating thermal noise

technique

quadrature-phase differential interferometer

Bellon et al., *Opt. Commun.* 207, 2002

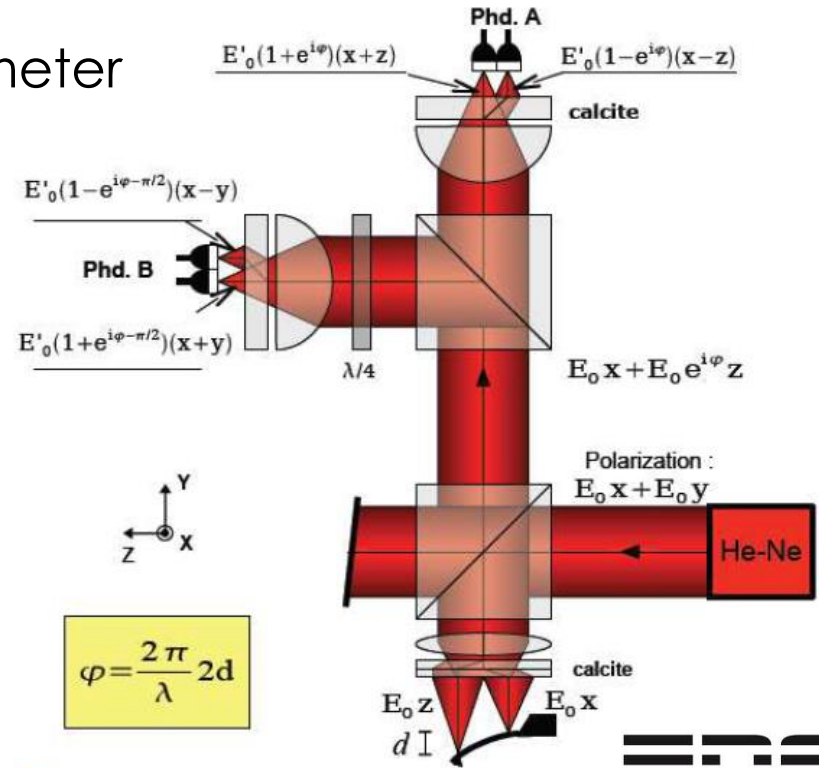
Paolino et al., *Rev. Sci. Instrum.* 84, 2013

- key points

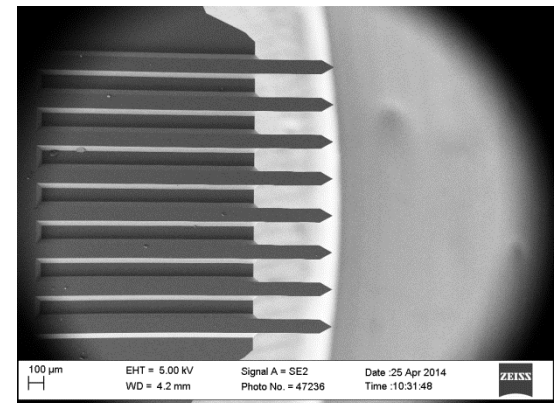
- AFM micro-cantilevers
- linearly-polarized light

talk by L. Bellon in this session

- nearly-common-path Michelson
- high noise rejection
- very low drift



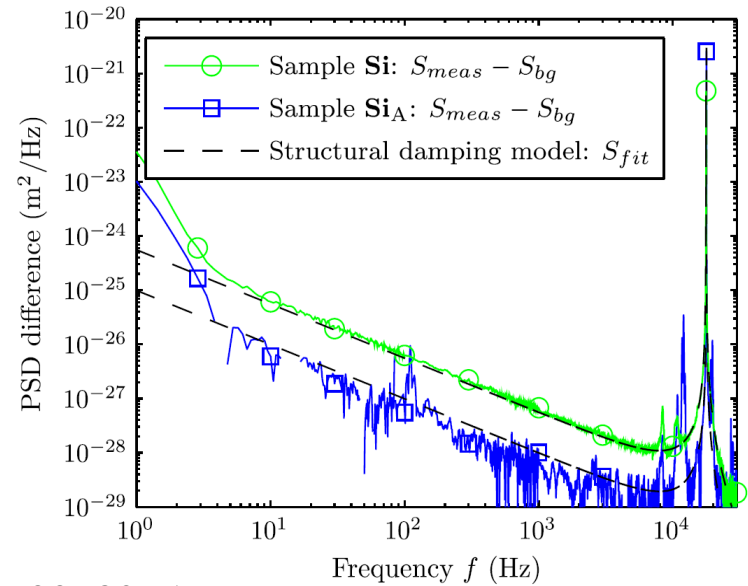
Bellon, Ciliberto et autres, *Opt. Comm.* (2002).



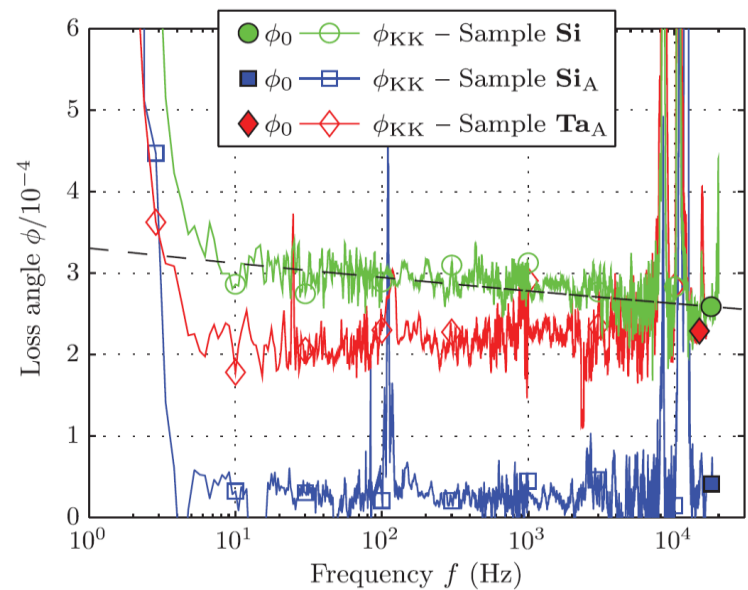
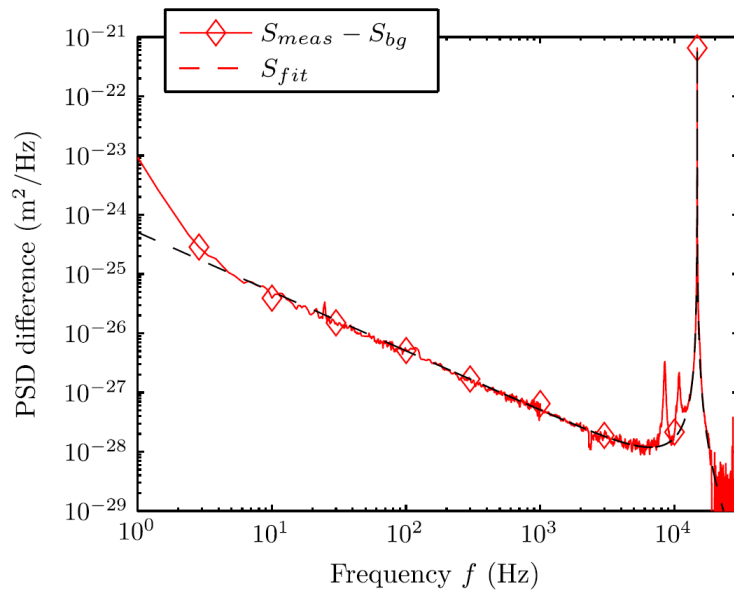
SiO₂ and Ta₂O₅

- $1/f$ noise – Saulson model confirmed
- f -independent loss after annealing

Coating	\mathcal{D}	$\phi_c \times 10^4$
SiO ₂ as coated	0.40 ± 0.02	$6.0 \pm 0.3(\pm 0.5)$
SiO ₂ annealed	0.41 ± 0.02	$0.62 \pm 0.05(\pm 0.43)$
Ta ₂ O ₅ annealed	0.45 ± 0.02	$4.7 \pm 0.2(\pm 0.4)$



Li et al., *Phys. Rev. D* 89, 2014



new mono-layer samples

better substrate measurements → improved coating loss estimations

measured dilution factor
$$D \approx 1 - (f_s/f_{cc})^2 \mu_s / (\mu_s + \mu_c)$$

- SiO₂

as deposited: $\Phi_c = 6.0 \pm 0.8 \text{ e-4}$ → $\Phi_c = 5.9 \pm 0.3 \text{ e-4}$

annealed: $\Phi_c = 6.2 \pm 4.3 \text{ e-5}$ → $\Phi_c = 3.1 \pm 0.8 \text{ e-5}$

- Ta₂O₅

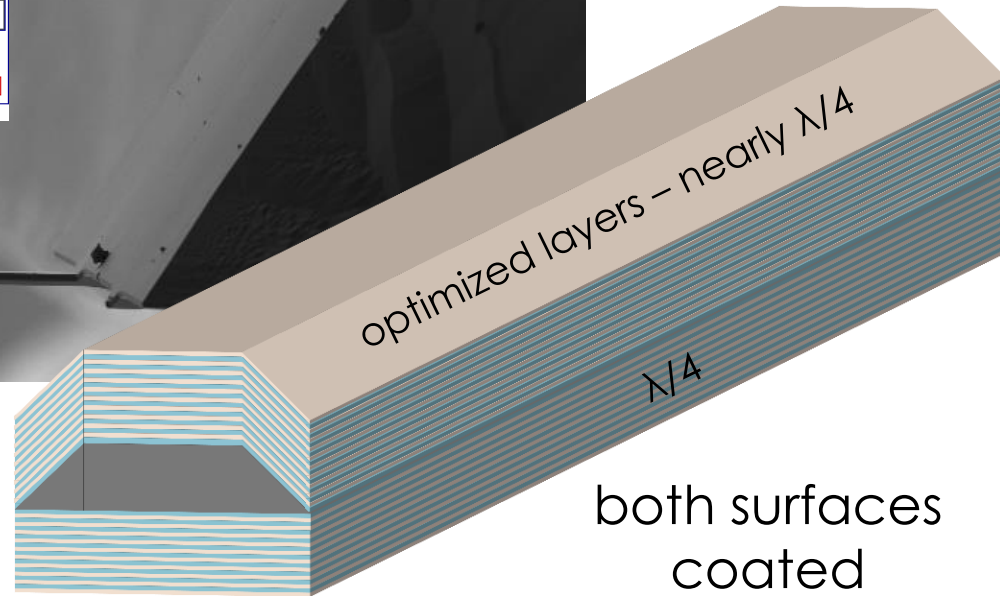
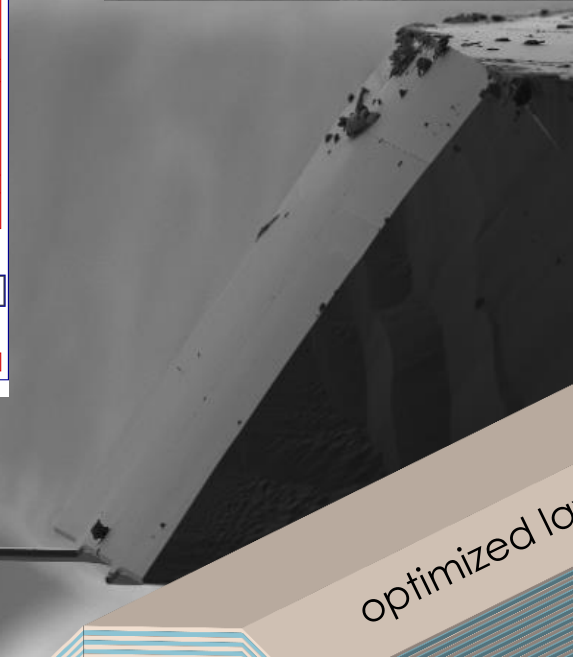
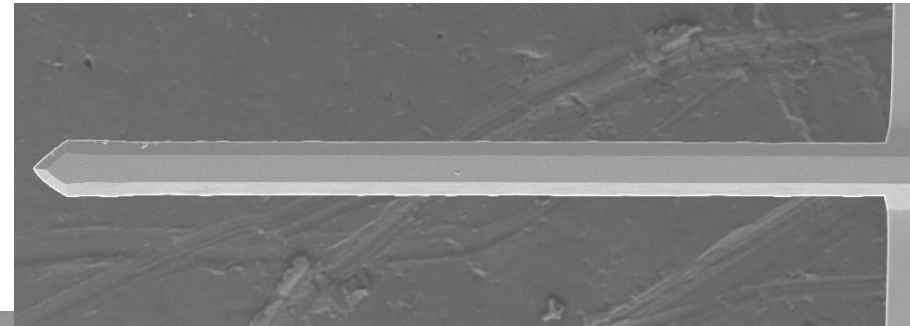
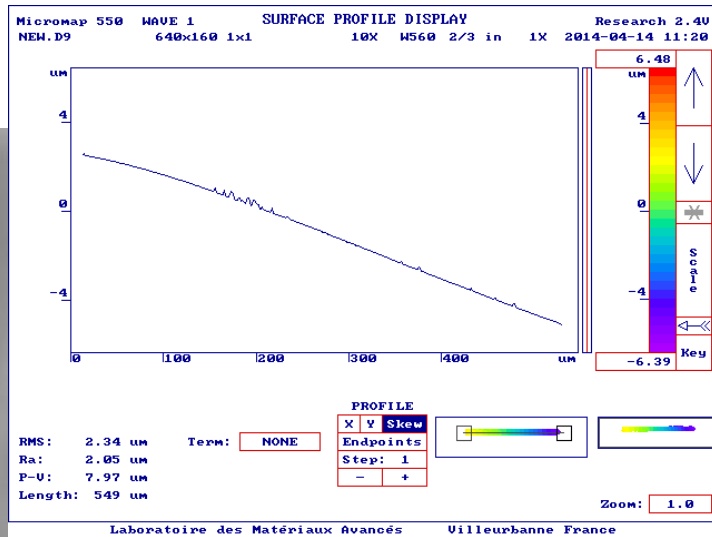
annealed: $\Phi_c = 4.7 \pm 0.6 \text{ e-4}$ → ... coming soon

in agreement with
GeNS measurements



stacks

- quarter-wavelength coatings
plain Ta₂O₅ and SiO₂ layers



– straight coated cantilevers –
technique developed at LMA

results

- $(LH)_5$

measured: $\Phi_c = 3.1 \pm 0.3 \text{ e-4}$

expected: $\Phi_c = 2.8 \pm 0.4 \text{ e-4}$
linear combination of mono-layer loss

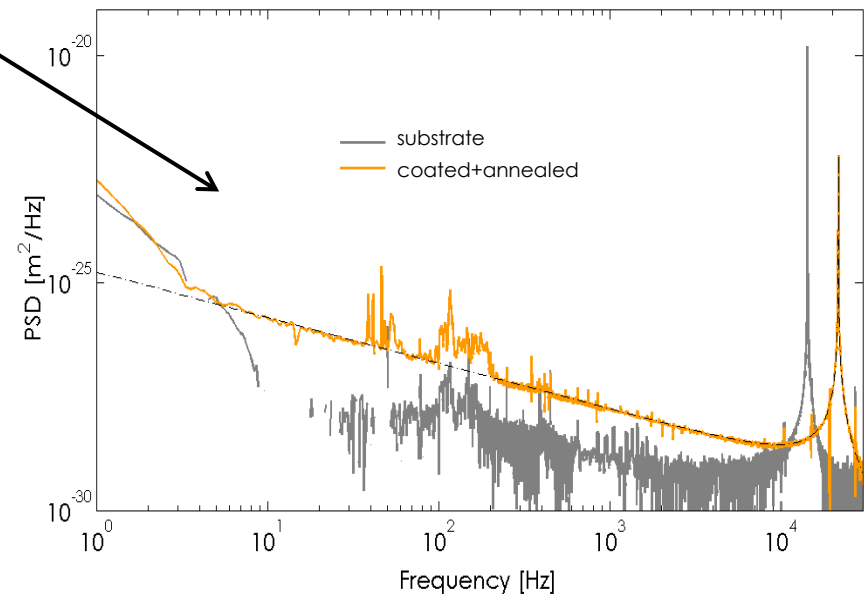
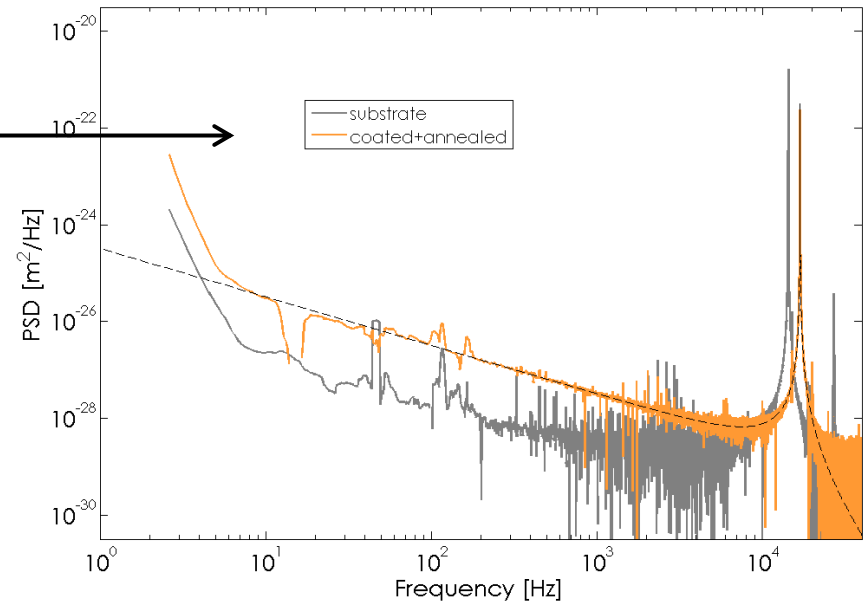
- $(LH)_{10}$

measured: $\Phi_c = 3.9 \pm 0.2 \text{ e-4}$

expected: $\Phi_c = 2.6 \pm 0.3 \text{ e-4}$
linear combination of mono-layer loss

same as with macro-cantilevers ?

M. Granata & al., *GWADW*, Waikoloa, 2012



coating structure and mechanical loss

Raman in a nutshell

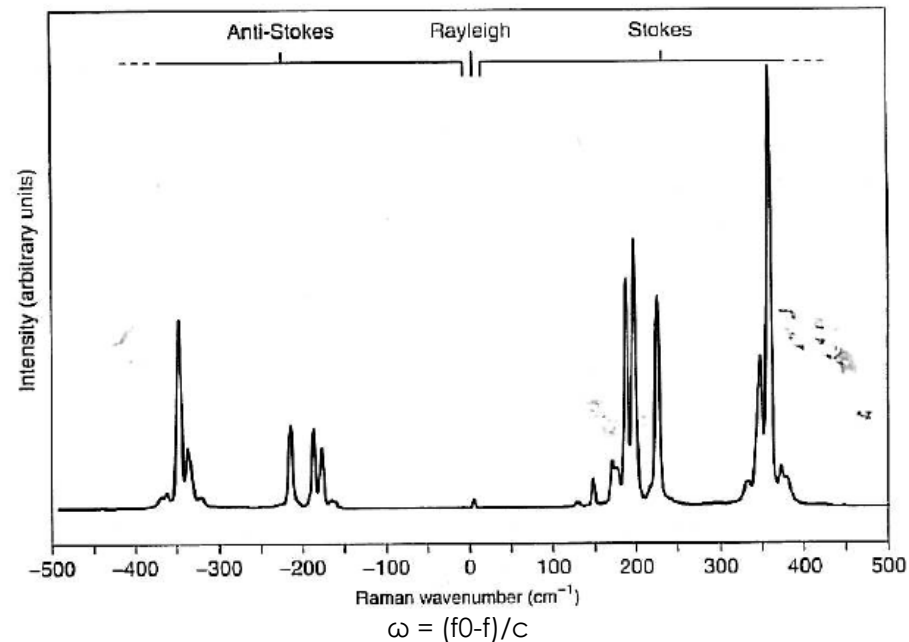
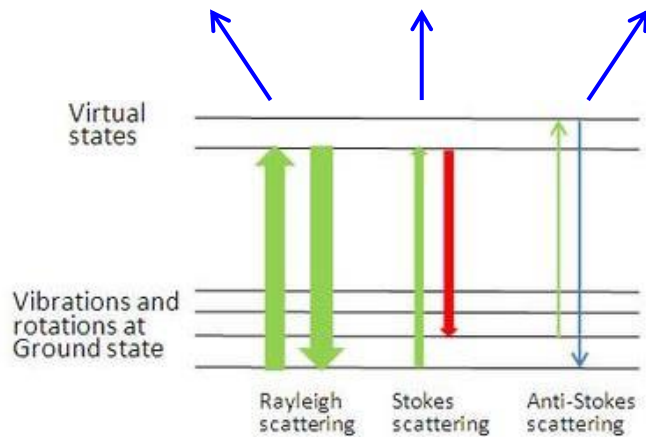
laser $\mathbf{E} = \mathbf{E}_0 \cos(2\pi f_0 t) \rightarrow$ dipole
 polarizability & normal coordinates

$$\mathbf{p} = \alpha \mathbf{E}$$

$$\alpha(Q_k) \sim \alpha_0 + Q_k \partial\alpha/\partial Q_k$$

$$Q_k = Q_{k0} \cos(2\pi f_k t)$$

$$\rightarrow \mathbf{p} = \mathbf{p}(f_0) + \mathbf{p}(f_0 - f_k) + \mathbf{p}(f_0 + f_k)$$

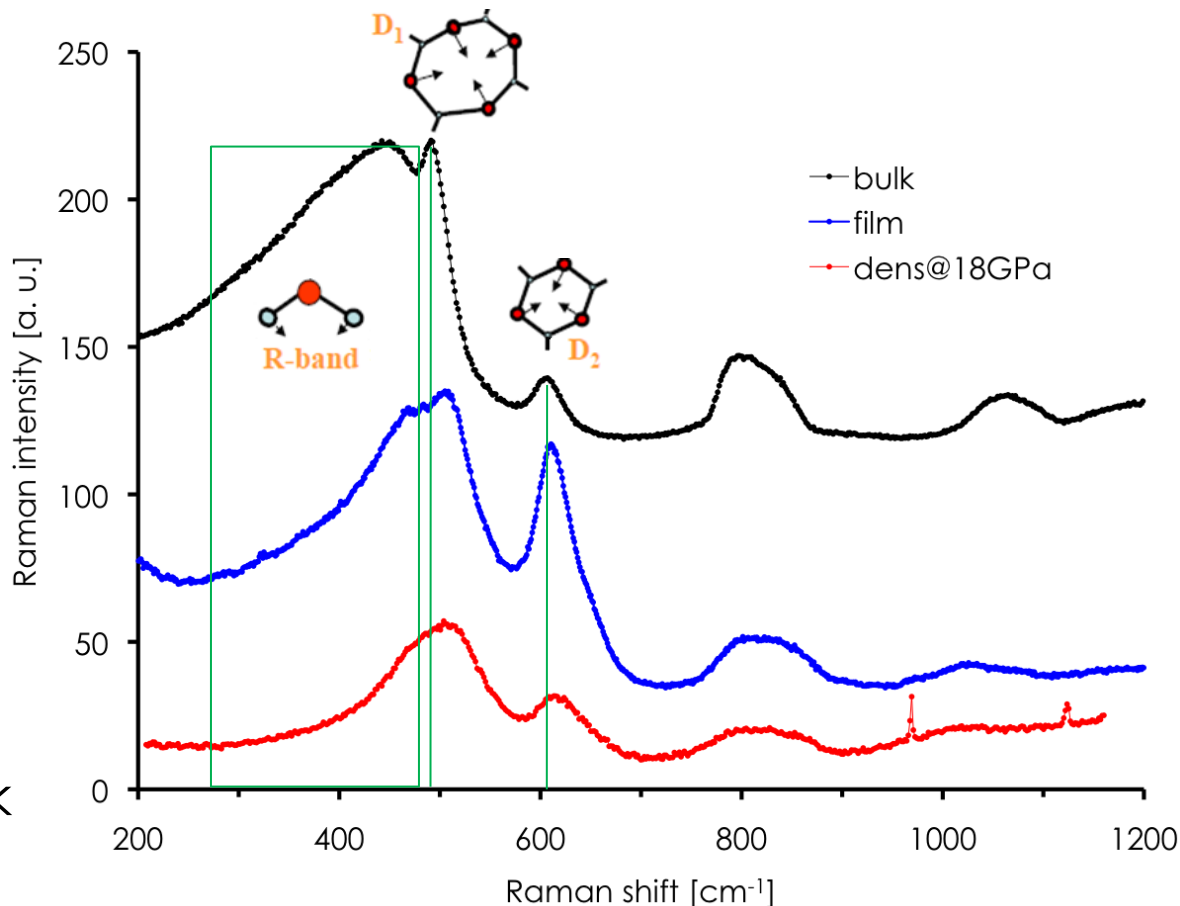
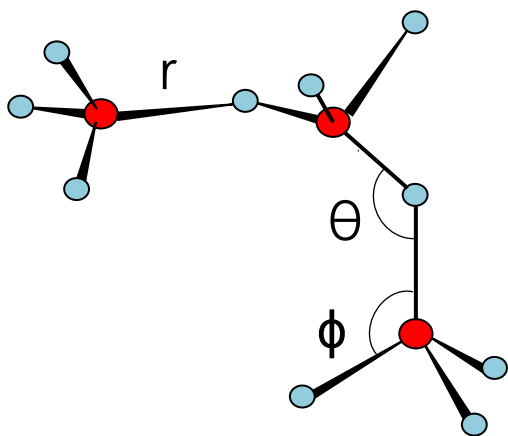


\rightarrow spectrum of vibrational transitions

talk by V. Martinez
 in this session

P. Vandenabeele
Practical Raman Spectroscopy
 Wiley, 2013

SiO₂



- film
 - different R-band
 - shifted peaks
 - higher D2 intensity
- similar to densified bulk

in agreement with density measurements:

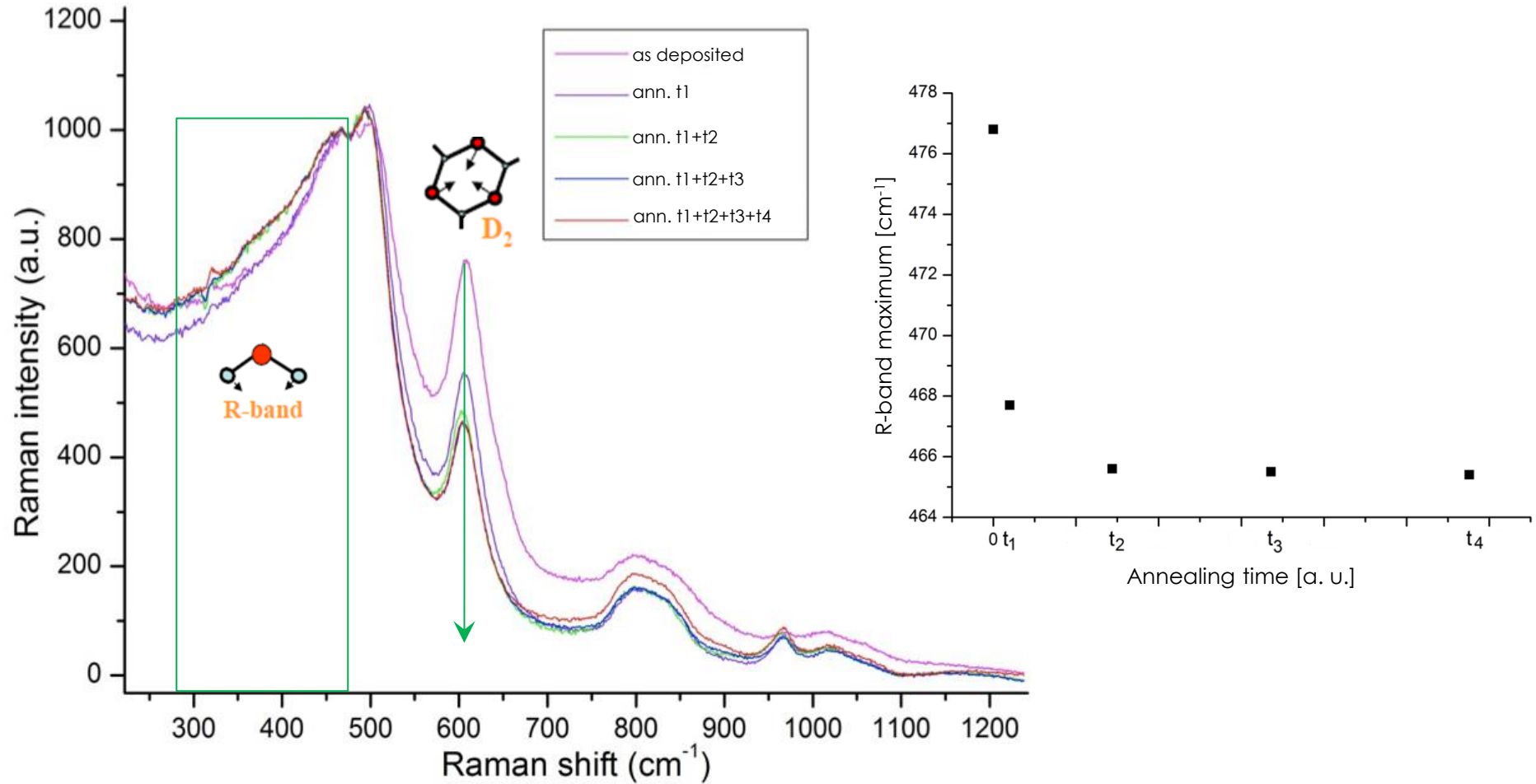
$$\rho_{\text{bulk}} = 2.20 \text{ g/cm}^3$$

$$\rho_{\text{film}} = 2.47 \text{ g/cm}^3$$

peak identification

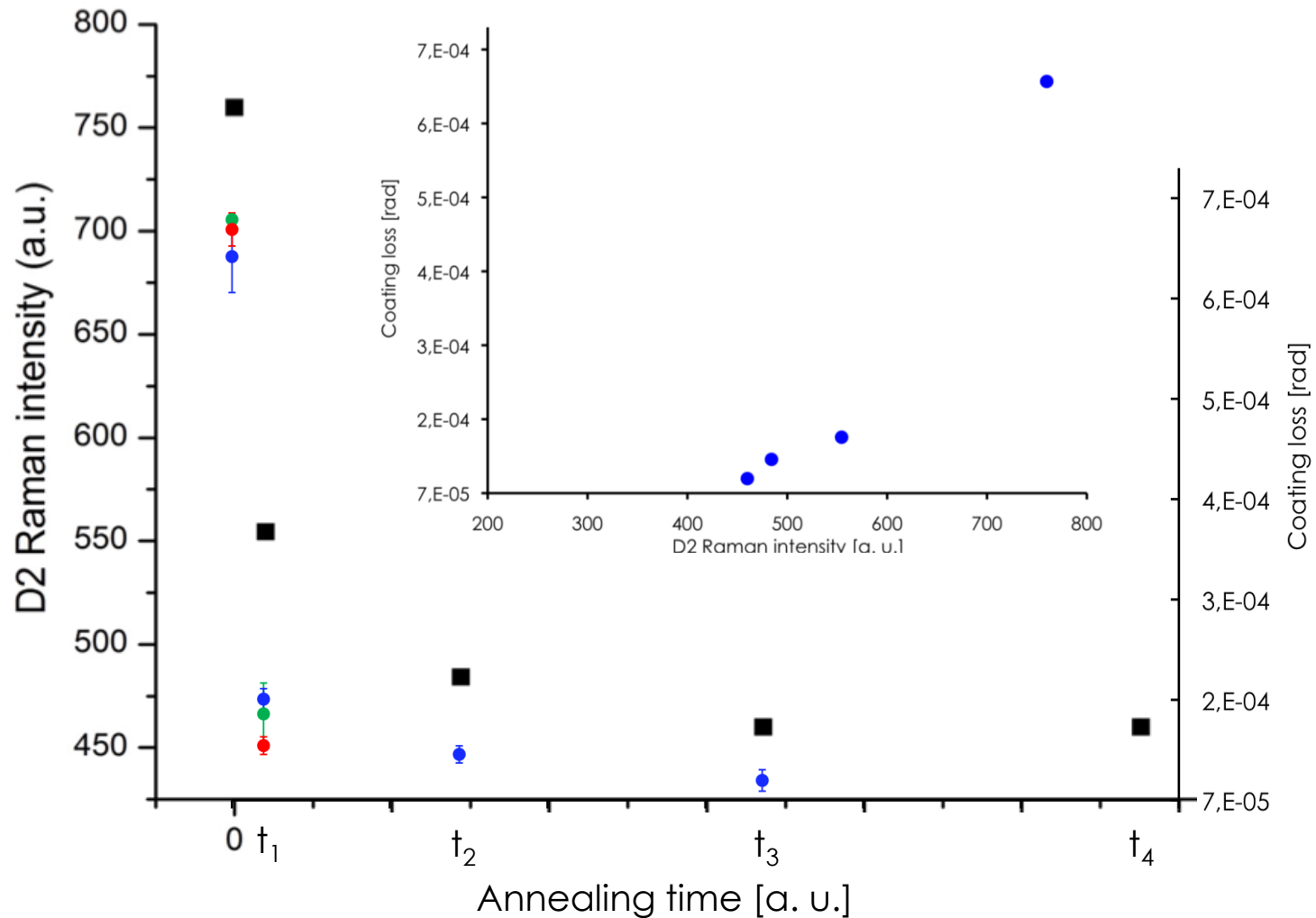
Galeener, *J. Non-Cryst. Solids* 71, 1985

annealing



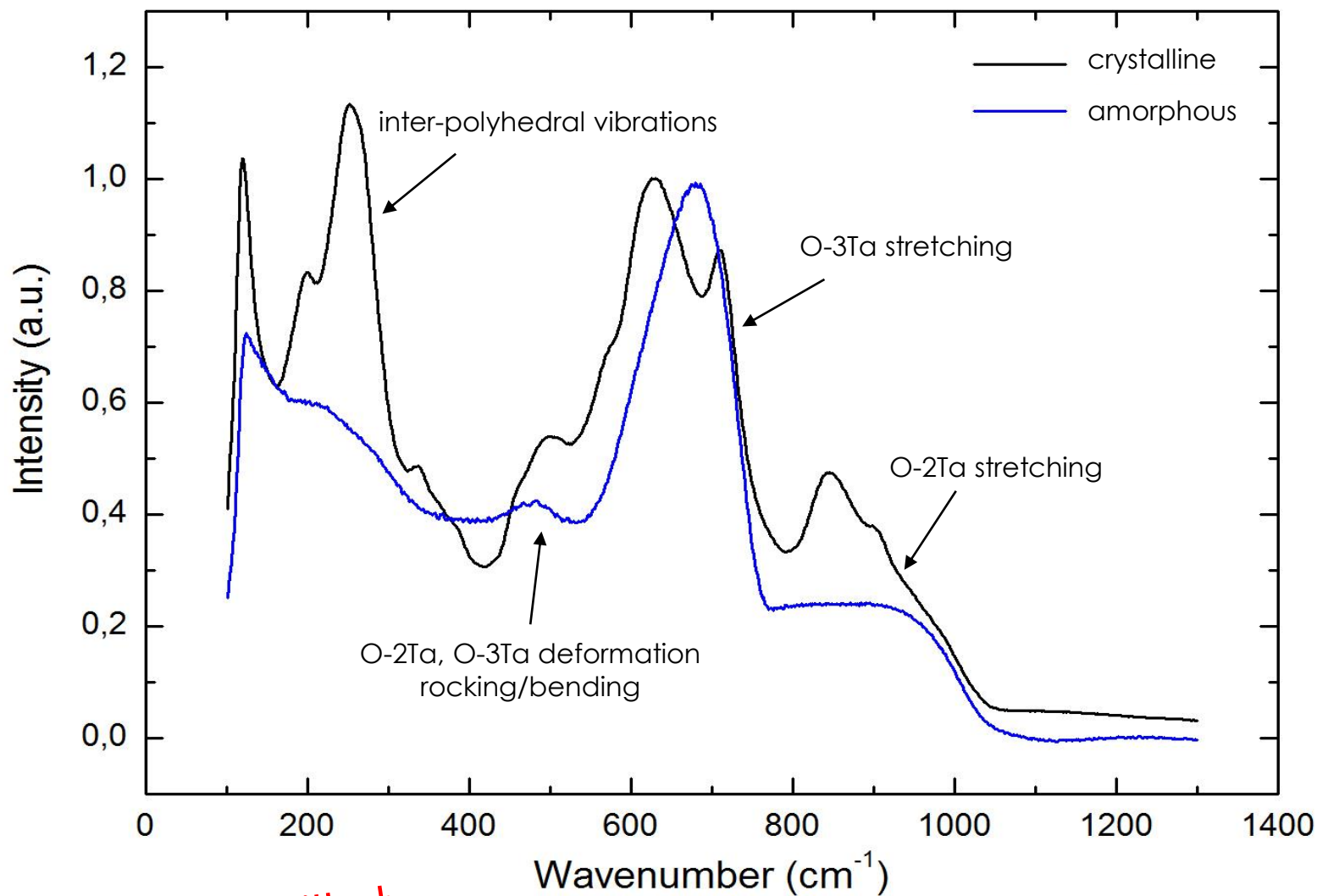
- remarkable evolution wrt annealing time
 - modification of the R-band → different θ distribution
 - reduction of D₂ peak

SiO₂ structure and loss



- loss measured on 3 SiO₂ cantilever blades
- close correlation between D2 spectral evolution and loss

Ta₂O₅

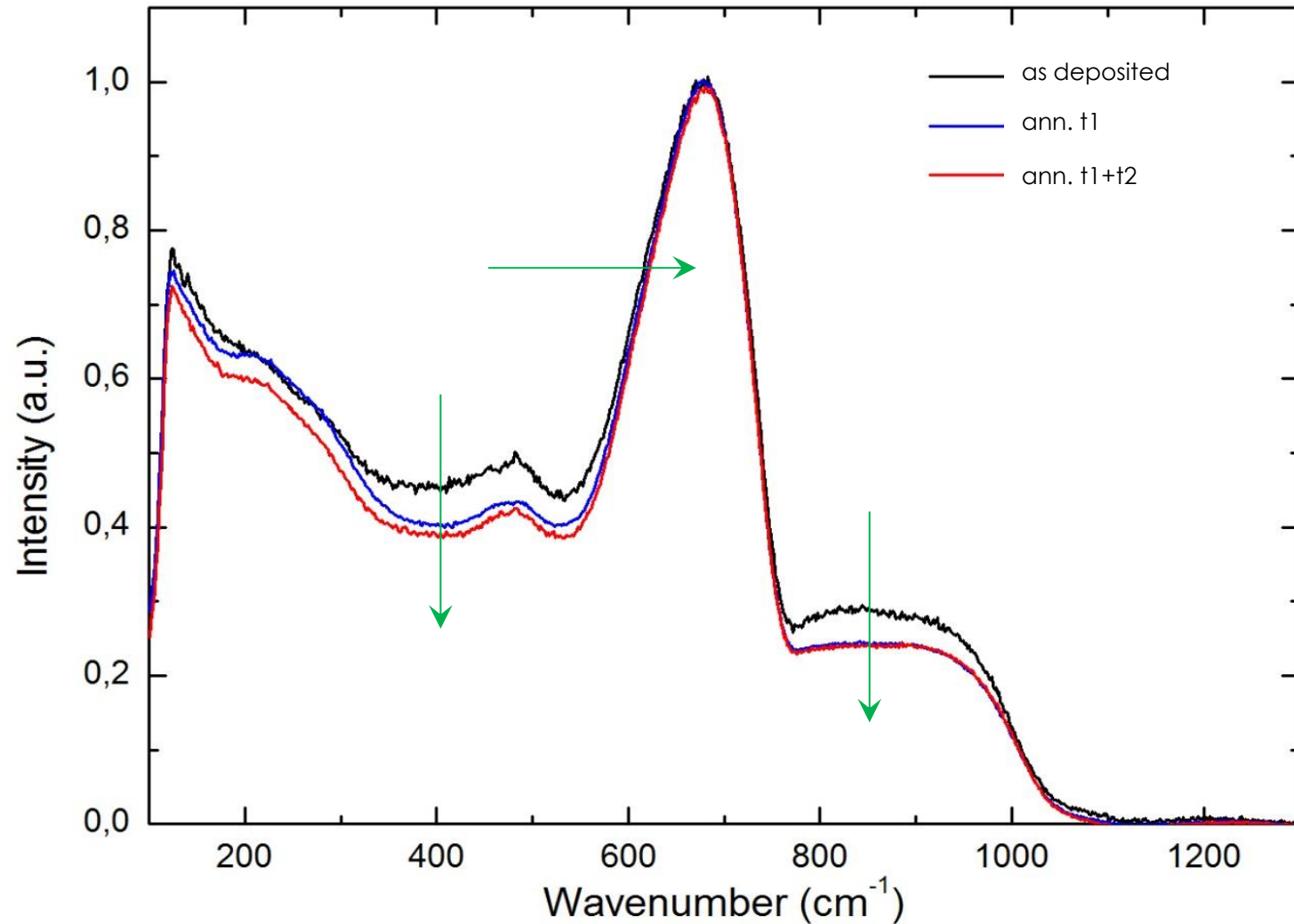


poster by E. Coillet

peak identification

C. Joseph, *J. Raman Spectrosc.* 43, 2012

annealing

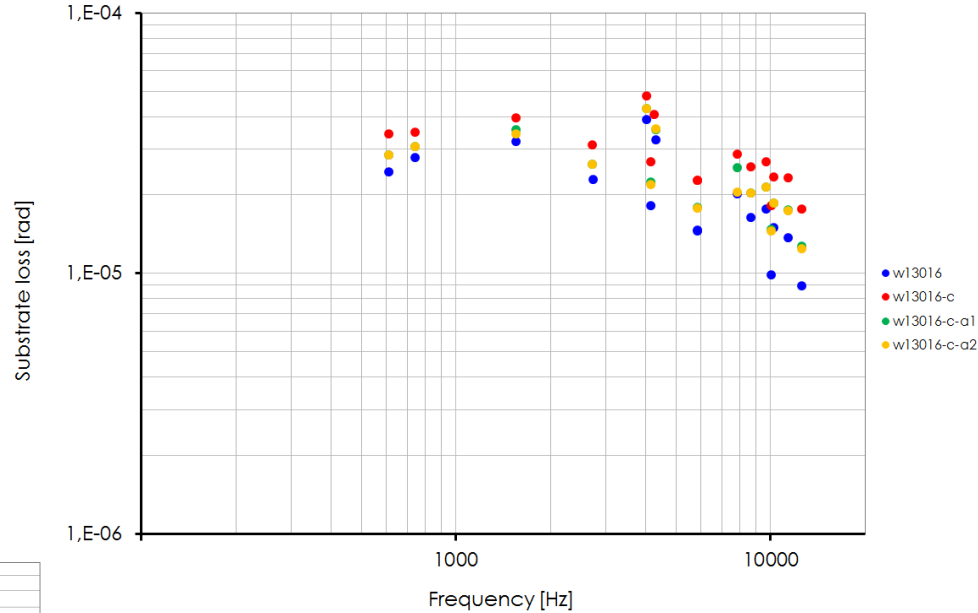


- evolution with 1st annealing
- weaker changes with 2nd annealing

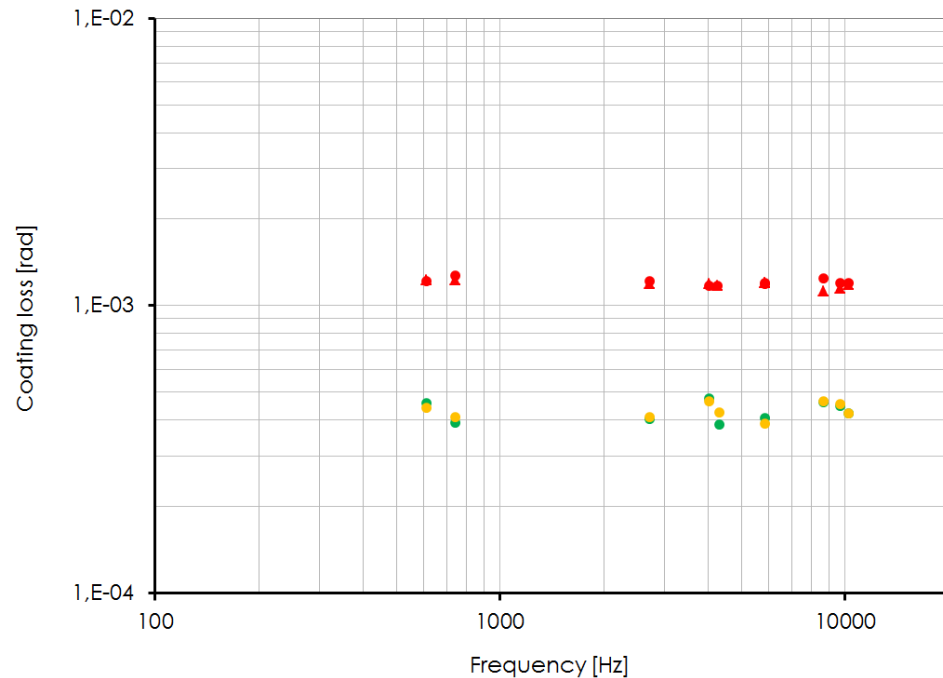
Ta2O5 structure and loss

- loss measured on Si disks
 - as dep.: $\Phi_c = 1.2 \pm 0.1 \text{ e-}3$
 - ann. - t1: $\Phi_c = 4.3 \pm 0.3 \text{ e-}4$
 - ann. - t2: $\Phi_c = 4.3 \pm 0.3 \text{ e-}4$

measured dilution factor
 $D \approx 1 - (f_s/f_{cd})^2 \mu_s / (\mu_s + \mu_c)$



- no evolution after 1st annealing
 work ongoing to correlate loss to Raman spectra



summary

summary

- mode-dependent thermoelastic damping confirmed
 - paper with model and measurements in preparation
- coating thermal noise measurements
 - improving mono-layer characterization
 - study ongoing on high-reflective stacks
- Raman spectroscopy to investigate coating structure
 - first observation of SiO₂ structure/loss correlation
 - preliminary results on Ta₂O₅ – work ongoing

acknowledgements

Fédération de Physique André-Marie Ampère (FRAMA)